

January 1993 Revised November 1999

# 74ABT273 Octal D-Type Flip-Flop

#### **General Description**

The ABT273 has eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset  $(\overline{\text{MR}})$  inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output.

All outputs will be forced LOW independently of Clock or Data inputs by a LOW voltage level on the MR input. The device is useful for applications where the true output only is required and the Clock and Master Reset are common to all storage elements.

#### **Features**

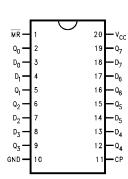
- Eight edge-triggered D-type flip-flops
- Buffered common clock
- Buffered, asynchronous Master Reset
- See ABT377 for clock enable version
- See ABT373 for transparent latch version
- See ABT374 for 3-STATE version
- Output sink capability of 64 mA, source capability of 32 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability
- Disable time less than enable time to avoid bus contention

## **Ordering Code:**

Order Number	Package Number	Package Description
74ABT273CSC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ABT273CSJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74ABT273CMSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74ABT273CMTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code

#### **Connection Diagram**



#### **Pin Descriptions**

Pin Names	Description
D <sub>0</sub> –D <sub>7</sub>	Data Inputs
MR	Master Reset (Active LOW)
CP	Clock Pulse Input (Active Rising Edge)
Q <sub>0</sub> –Q <sub>7</sub>	Data Outputs

© 1999 Fairchild Semiconductor Corporation

DS011549

www.fairchildsemi.com

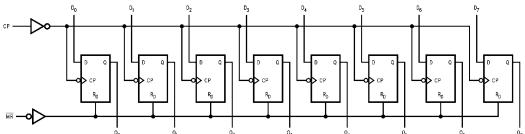
## **Truth Table**

Operating Mode		Output		
	MR	СР	D <sub>n</sub>	$Q_n$
Reset (Clear)	L	Х	Х	L
Load "1"	Н	~	h	Н
Load "0"	Н	~	I	L

- H = HIGH Voltage Level steady state
  h = HIGH Voltage Level one setup time prior to the LOW-to-HIGH clock transition
  L = LOW Voltage Level steady state
  I = LOW Voltage Level one setup time prior to the LOW-to-HIGH clock transition
  X = Immaterial

  = LOW-to-HIGH clock transition

## **Logic Diagram**



 $\dot{o}_0$   $\dot{o}_1$   $\dot{o}_2$   $\dot{o}_3$   $\dot{o}_4$   $\dot{o}_5$   $\dot{o}_6$  Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

## **Absolute Maximum Ratings**(Note 1)

**Recommended Operating Conditions** 

-65°C to +150°C Storage Temperature -55°C to +125°C Ambient Temperature under Bias

Junction Temperature under Bias -55°C to +150°C

V<sub>CC</sub> Pin Potential to Ground Pin

-0.5V to +7.0VInput Voltage (Note 2) -0.5V to +7.0V-30 mA to +5.0 mA

Input Current (Note 2)

Voltage Applied to Any Output

in the Disabled or

Power-Off State -0.5V to +4.75Vin the HIGH State -0.5V to  $V_{CC}$ 

Current Applied to Output

in LOW State (Max) twice the rated I<sub>OL</sub> (mA)

DC Latchup Source Current -500 mA

(Across Comm Operating Range)

Over Voltage Latchup  $V_{CC} + 4.5V$  Free Air Ambient Temperature -40°C to +85°C +4.5V to +5.5V

Supply Voltage Minimum Input Edge Rate ( $\Delta V/\Delta t$ )

50 mV/ns Data Input Enable Input 20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	V <sub>CC</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			8.0	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage	2.5			V	Min	$I_{OH} = -3 \text{ mA}$
		2.0					$I_{OH} = -32 \text{ mA}$
V <sub>OL</sub>	Output LOW Voltage			0.55	V	Min	I <sub>OL</sub> = 64 mA
I <sub>IH</sub>	Input HIGH Current			1	μА	Max	V <sub>IN</sub> = 2.7V (Note 3)
				1	μΛ	IVIAA	$V_{IN} = V_{CC}$
I <sub>BVI</sub>	Input HIGH Current			7	μА	Max	V <sub>IN</sub> = 7.0V
	Breakdown Test			,	μΛ	IVIAX	VIN - 7.0V
I <sub>IL</sub>	Input LOW Current			-1		Max	V <sub>IN</sub> = 0.5V (Note 3)
				-1	μΑ	IVIAX	$V_{IN} = 0.0V$
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	I <sub>ID</sub> = 1.9 μA
							All Other Pins Grounded
Ios	Output Short-Circuit Current	-100		-275	mA	Max	V <sub>OUT</sub> = 0.0V
I <sub>CEX</sub>	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC}$
I <sub>CCH</sub>	Power Supply Current			50	μΑ	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current			30	mA	Max	All Outputs LOW
I <sub>CCT</sub>	Maximum I <sub>CC</sub> /Input Outputs Enabled			1.5	mA	Max	$V_{I} = V_{CC} - 2.1V$
							Data Input V <sub>I</sub> = V <sub>CC</sub> - 2.1V
							All Others at V <sub>CC</sub> or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub> No Load			0.3	mA/	Max	Outputs Open (Note 4)
					MHz	IVIAX	One Bit Toggling, 50% Duty Cycle

Note 3: Guaranteed but not tested.

Note 4: For 8 bits toggling,  $I_{CCD} < 0.5 \text{ mA/MHz}.$ 

#### **AC Electrical Characteristics**

(SSOIC package)

Symbol	Parameter	$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_{A} = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = 4.5V \text{ to } 5.5V$ $C_{L} = 50 \text{ pF}$		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_L = 50 \text{ pF}$		Units	
		Min	Тур	Max	Min	Max	Min	Max	
f <sub>MAX</sub>	Maximum Clock Frequency	150	200		150		150		MHz
t <sub>PLH</sub>	Propagation Delay	2.0		6.0	1.0	7.0	2.0	6.0	ns
$t_{PHL}$	CP to O <sub>n</sub>	2.8		6.8	1.0	7.5	2.8	6.8	115
t <sub>PHL</sub>	Propagation Delay MR to On	2.5		7.4	1.0	8.2	2.5	7.4	ns

## **AC Operating Requirements**

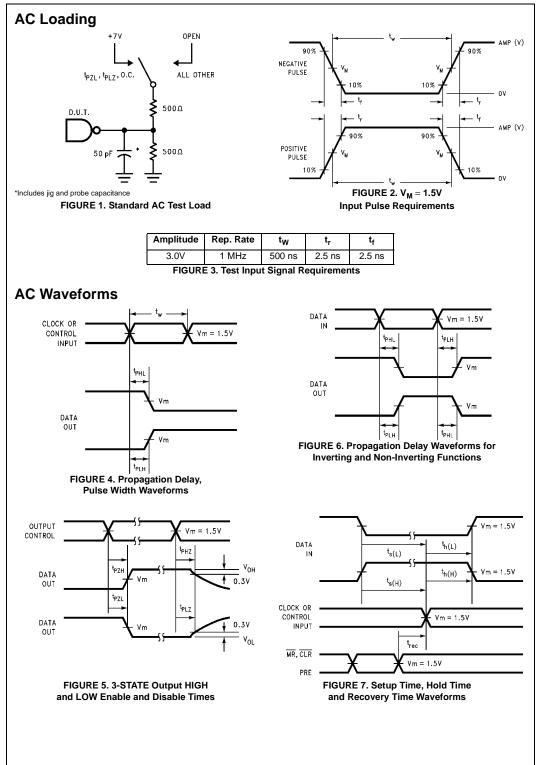
Symbol	Parameter	$T_A = +25$ °C $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$		$T_A = -55^{\circ}\text{C to } +125^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_L = 50 \text{ pF}$		$T_A = -40^{\circ}\text{C to } +85^{\circ}\text{C}$ $V_{CC} = 4.5\text{V to } 5.5\text{V}$ $C_L = 50 \text{ pF}$		Units
		Min	Max	Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time, HIGH	2.0		2.0		2.0		ns
t <sub>S</sub> (L)	or LOW D <sub>n</sub> to CP	2.5		2.5		2.5		115
t <sub>H</sub> (H)	Hold Time, HIGH	1.2		1.4		1.2		ns
t <sub>H</sub> (L)	or LOW D <sub>n</sub> to CP	1.2		1.4		1.2		115
t <sub>W</sub> (H)	Pulse Width, CP,	3.3		3.3		3.3		ns
t <sub>W</sub> (L)	HIGH or LOW	3.3		3.3		3.3		115
t <sub>W</sub> (L)	Master Reset Pulse	3.3		3.3		3.3		ns
	Width, LOW							
t <sub>REC</sub>	Recovery Time	2.0		2.0		2.0		ns
	MR to CP							

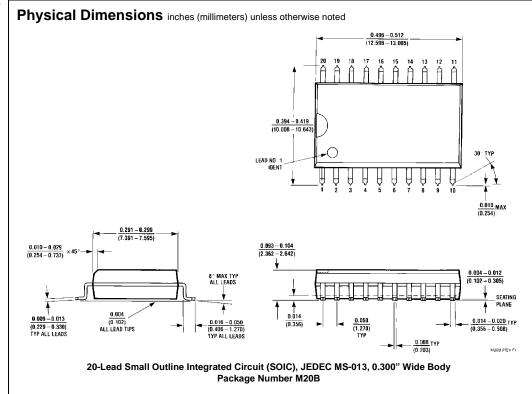
## Capacitance

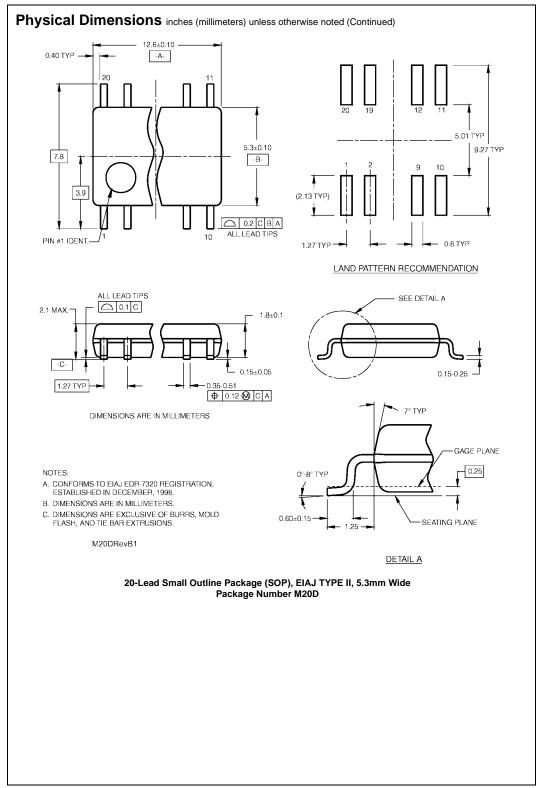
(SOIC package)

Symbol	mbol Parameter		Units	Conditions T <sub>A</sub> = 25°C
C <sub>IN</sub>	Input Capacitance	5	pF	V <sub>CC</sub> = 0V
C <sub>OUT</sub> (Note 5)	Output Capacitance	9	pF	V <sub>CC</sub> = 5.0V

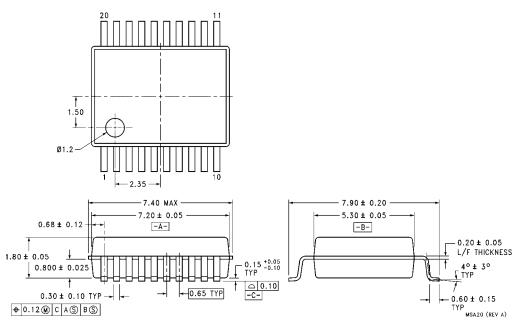
 $\textbf{Note 5: } C_{OUT} \text{ is measured at frequency } f = 1 \text{ MHz, per MIL-STD-833, Method 3012.}$ 



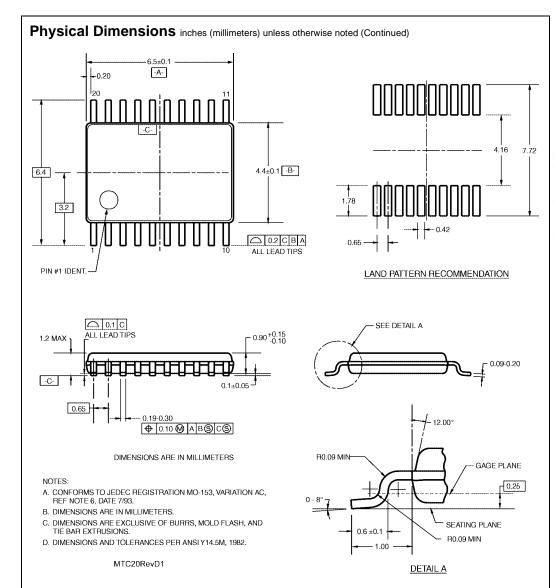




## Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20



# 20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC20

Fairchild does not assume any responsibility for use of any circuitry described, no circuit patent licenses are implied and Fairchild reserves the right at any time without notice to change said circuitry and specifications.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
- A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

www.fairchildsemi.com

www.fairchildsemi.com